

Issue Classification	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10521610	IWAKI ET AL.
	Examiner	Art Unit
	Cruz, Magda	2851

Cruz, Magda <i>mc</i> (Assistant Examiner)	01/14/2008 (Date)	DIANE I. LEE SUPERVISORY PATENT EXAMINER	Total Claims Allowed: 12
<i>Kathleen Carter</i> (Legal Instruments Examiner)	<i>1/17/08</i> (Date)	Diane Lee <i>DR</i> (Primary Examiner)	1/17/08 (Date) O.G: Print Claim(s) 1 O.G. Print Figure 3